

connectivity PAGE 1/10 TITLE DOC No. PCI EXPRESS GEN 5.0 SPEC REVISION : STATUS : A0 OFFICIAL RELEASE DATE : CLASSIFICATION : 2023/09/20 2023/09/20

1.0 SCOPE

This specification is applicable to the termination characteristics of PCI Express Card Electromechanical Specification and certain customer specifications not covered by the PCI-SIG document.

2.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

The following document for part of this specification to the extent specified here with. In the event of conflict between the requirements of the specification and the referenced documents. This specification shall take precedence.

EIA-364 Test methods for electrical connectors
MIL-STD-202F Test methods for electrical component parts
Underwriters' Laboratories, Inc.
UL-STD-94Tests for flammability of plastic materials for parts in devices and appliances.

3.0 REQUIREMENTS

3.1 Materials

3.1.1 Insulator

High temperature thermoplastic, UL94V-0 rated Color- Black

3.1.2 Contacts

Copper alloy

Contact area: 15micro inches minimum of gold

Solder area: Matte tin plating

Under plate: Nickel under plating overall

3.1.3 Solder pad

Stainless steel Solder area- Matte tin plating Under plating- Nickel under plating overall

3.1.4 Ground pin Stainless steel



PAGE 2/10

TITLE PAGE 2/10 DOC No. REVISION : STATUS : PCI EXPRESS GEN 5.0 SPEC A0 OFFICIAL RELEASE DATE : CLASSIFICATION : 2023/09/20

3.2 Ratings

- 3.2.1 Voltage: 30 Volts AC/DC for all contacts
- 3.2.2 Current: 1.1A max per contact
- 3.2.3None operating Temperature: -55° C ~ 105° C
- 3.2.4 Temperature: Field:65 $^\circ\,$ C

4.0 TEST REQUIREMENTS AND PROCEDURES SUMMARY

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
4.1	Examination of P	EIA-364-18 Visual, dimensional and	Meets requirements
	roduct	functional inspection	No physical damage.

ELECTRICAL REQUIREMENT

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
4.2	Low Level Contact Resistance	EIA-364-23 Subject mated connector with a max. voltage of 20mV and current of 100mA	Initial:30 mΩmax Final:ΔR: 10 mΩmax
4.3	Dielectric withstanding Voltage	EIA-364-20 C-B Subject unmated connector with a voltage of 500 VAC for 1.0 minute between adjacent terminals. Current leakage:0.5A Max.	No Breakdown



PAGE 3/10

TITLE

PCI EXPRESS GEN 5.0 SPEC

DOC No.		
REVISION :	STATUS :	
A0	OFFICIAL RELEASE	
DATE :	CLASSIFICATION :	
2023/09/20		

		EIA-364-21	
	Insulation	Subject unmated and	
		dismount connectors with a.	1000M Ohma min
4.4	Resistance	voltage of 500 VDC between	
		adjacent terminals and	
		between terminal to ground.	
		EIA 364-70 method 2	
		The sample size is a minimum	
		of three mated connectors.	
		The sample shall be soldered	
		on a board with the	
		appropriate footprint.	
		Wire the nine power pins (B1,	
		B2, B3, A2, A3, B8, A9, A10,	
		and B10) and the nine nearest	
		ground pins (A4, B4, B7, A12,	1.1 A per pin minimum
		B13, A15, B16, B18, and A18)	The temperature rise
	Contact current	in a series circuit. The mated	above ambient shall
4.5	rating	Add-in Card is included in this	not exceed
	Tatilig	circuit. The Add-in Card	30℃. The ambient
		shall have 1 oz. copper traces	condition is still air at
		and its mating geometry shall	25℃.
		conform to the applicable PCI	
		Express drawings.	
		A thermocouple of 30 AWG or	
		less shall be placed on the	
		card edge-finger pad (pins B2	
		and A9) as close to the mating	
		contact as possible.	
		Conduct a temperature rise	
		vs. current test.	



PAGE 4/10

т	רו	

PCI EXPRESS GEN 5.0 SPEC

DOC No.		
REVISION :	STATUS :	
A0	OFFICIAL RELEASE	
DATE :	CLASSIFICATION :	
2023/09/20		

MECHANICAL REQUIREMENT

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
4.6	Insertion Force	Insert a steel blade of 1.70mm at a rate of 25.4mm per minute max See fig.1for blade details Per EIA-364-13	1.15N max per contact pair
4.7	Withdrawal Force	Withdrawal a steel blade of 1.44mm at a rate of 25.4mm per minute max See fig.1for blade details Per EIA-364-13	0.15N min per contact pair
4.8	Contact Retention Force	EIA-364-37 The end of a post shall be pulled in a perpendicular to base housing at a contact speed of 12.7 mm/ min.	5N min per terminal
4.9	Solder Pad Retention Force	EIA-364-37 Measure force to pull out terminals at a speed rate of 12.7mm/ min.	12N min
4.10	Durability	EIA-364-09 Mate/Un-mate P.C.B for 50 cycles at a rate of 25.4mm per minute max	Contact resistance: 10mΩchange from initial
4.11	Random Vibration	EIA-364-28,VII-D Test Subject mated connectors to 3.1g' s RMS. 15minutes in each of three mutually perpendicular planes.	Contact resistance: 10 mΩ change from initial Discontinuity : No greater than 1.0 micro second



PAGE 5/10

TITLE

PCI EXPRESS GEN 5.0 SPEC

DOC No.	
REVISION :	STATUS :
A0	OFFICIAL RELEASE
DATE :	CLASSIFICATION :
2023/09/20	

		FIA 264 07	Contact resistance:
		Accelerate of 50G 11 ms	10 mΩ
4 10	Mechanical Shoel	duration sine half wave	change from initial
4.12	Meenanical Shock	waveform ,3 cycle in each of	Discontinuity :
			No greater than 1.0
		then 5 axis	micro second

ENVIRONMENTAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
4.13	Cyclic Temperature and Humidity	EIA-364-31, Method III Subject mated specimens to 10 cycles(10 days) between 25 and 65°C at 90 to 95% R.H	Appearance: No damage
4.14	Temperature Life	EIA-364-17 method A Mated, $+105\pm3^{\circ}$ C for 168 hours	No evidence of physical damage and $\Delta R:10 \text{ m}\Omega$ max
4.15	Thermal Shock	EIA-364-32, method A, condition 1 Mated, 10 cycles of -55° +0/-3° C for 30 minutes. +25+10/-5° C for 5 minutes. +85+3/-0° C for 30 minutes. max.	No evidence of physical damage and $\Delta R:10 \text{ m}\Omega$ max
4.16	Solder ability	EIA-364-638 Steam age 1hrs. +/-5 min., Solder time to be 5+/-0.5 seconds at 245+/-5° C, using non-activated flux	90% of immersed area must show no voids and pin holes 90%吃锡
4.17	Resistance to soldering heat (Infrared reflow)	EIA-364-638 Average ramp rate: 1~4℃ per second Temperature(board surface): 260 +5℃/-5℃ Duration:20~40 seconds	Appearance: No damage



PAGE 6/10

TITLE

PCI EXPRESS GEN 5.0 SPEC

1				
	DOC No.			
REVISION :		STATUS :		
	A0	OFFICIAL RELEASE		
	DATE :			
	2023/09/20			

HIGH SPEED CHARACTERIZATION

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
4.18	Differential	Rise Time 250ps (20~80%)	$85\Omega \pm 15\Omega$
	Impedance		
4.19	Differential Insertion Loss	[-0.1 - 0.0875 *] dB for $f \le 16$ GHz; [3.5 - 0.3125* f] dB for 16 < $f \le 24$ GHz	EIA-364-101
4.20	Differential Return Loss	$[-20 + 0.625^* f] dB$ for $f \le 16 \text{ GHz}$; $[-24 + 0.875^* f] dB$ for $16 < f \le 24 \text{ GHz}$	EIA-364-108
4.21	Differential Near End Crosstalk	[1.5* f - 60] dB for $f \le 10 \text{ GHz}$; [(5/6)* f - 53.33] dB for $10 < f \le 24 \text{ GHz}$; ccICNNEXT $\le 250 \mu V$ for $f \max = 24 \text{ GHz}$	EIA-364-90
4.22	Differential Far End Crosstalk	[1.5* f - 60] dB for $f \le 10 \text{ GHz}$; [(5/6)* f - 53.33] dB for $10 < f \le 24 \text{ GHz}$; ccICNNEXT $\le 250 \mu V$ for $f \max = 24 \text{ GHz}$	EIA-364-90



PAGE 7/10

TITLE

PCI EXPRESS GEN 5.0 SPEC

DOC No.	
REVISION :	STATUS :
A0	OFFICIAL RELEASE
DATE :	CLASSIFICATION :
2023/09/20	

5.0 PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE:

Test or Examination	Test Group											
	A	В	С	D	E	F	G	Н	Ι	J	K	
Examination of Product	1,6	1,5	1,4	1,5	1,5	1,5	1,5	1,8	1,5	1,5	1,3	
Low Level Contact Resistance	2,5	2,4		2,4	2,4	2,4	2,4		2,4	2,4		
Dielectric withstanding Voltage								3,7				
Insulation Resistance								2,6				
Temperature Rise				3								
Insertion Force	3											
Withdrawal Force	4											
Contact Retention Force			2									
Solder Pad Retention Force			3									
Durability (Preconditioning)												
Durability		3										
Vibration									3			
Mechanical Shock										3		
Cyclic Temperature and Humidity						3		5				
Resistance to Solder Heats												
Temperature Life					3							
Thermal Shock							3	4				
Mixed Flowing Gas												
Thermal Disturbance												
Solderability											2	
Sample size	5	5	5	5	5	5	5	5	5	5	5	

NOTE: (a) Numbers indicate sequence in which tests are performed.(b) Discontinuities shall not take place in this test group, during tests.



PAGE 8	PAGE 8/10						
TITLE	DOC No.						
	REVISION :	STATUS :					
PCI EXPRESS GEN 5.0 SPEC	A0	OFFICIAL RELEASE					
	DATE :						
	2023/09/20						

6.0 PACKAGING

Parts shall be packed in trays and protected against damage during handling, transportation and storage.

7.0 Recommended IR Reflow Profile (Lead-free)

